

<b>Search Notes</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/645,516	ONO ET AL.
	Examiner José R. Díaz	Art Unit 2815

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	149	8/3/2005	JRD
438	163	8/3/2005	JRD
438	301	8/3/2005	JRD